Belyakov Vladimir V. Exam Schedule

Fri, 25 Dec	12:45 — 14:20	ATT Information and measurement systems in microelectronics S16-401, S16-402 Q ДОТ
Tue, 26 Jan	09:00 — 13:00	EXAM Information and measurement systems in microelectronics S16-401, S16-402 ▼ ДОТ